Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/554,263	KIM, SUKYOON
Examiner	Art Unit
David E. Bochna	3679

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
Updated the previous search	7/2/2007	DB
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